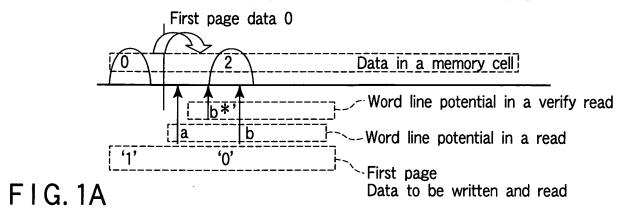
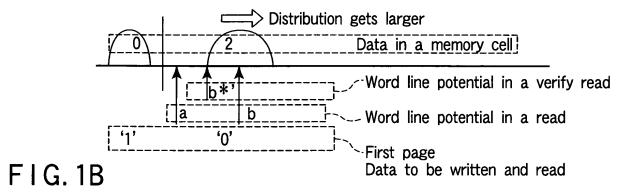
Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 1 of 42

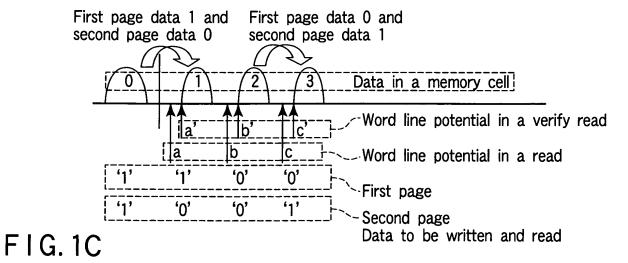
After writing the first page and before writing the second page



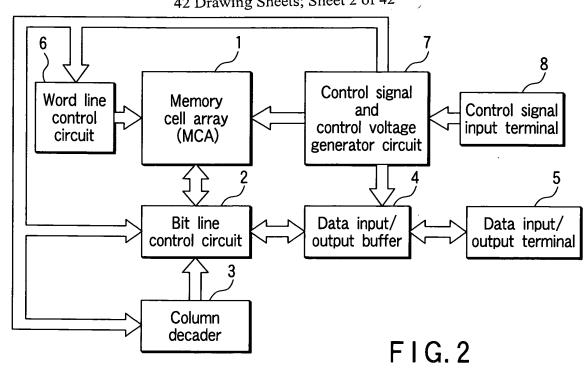
Before writing the second page and after writing the adjacent cells

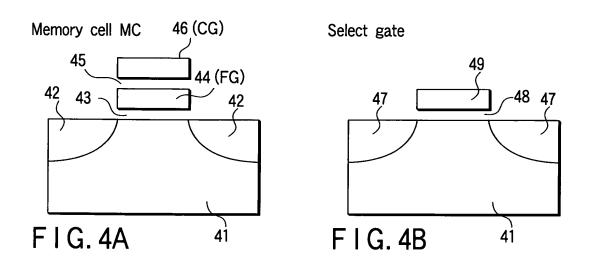


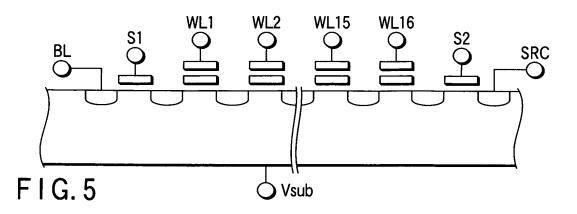
After writing the second page



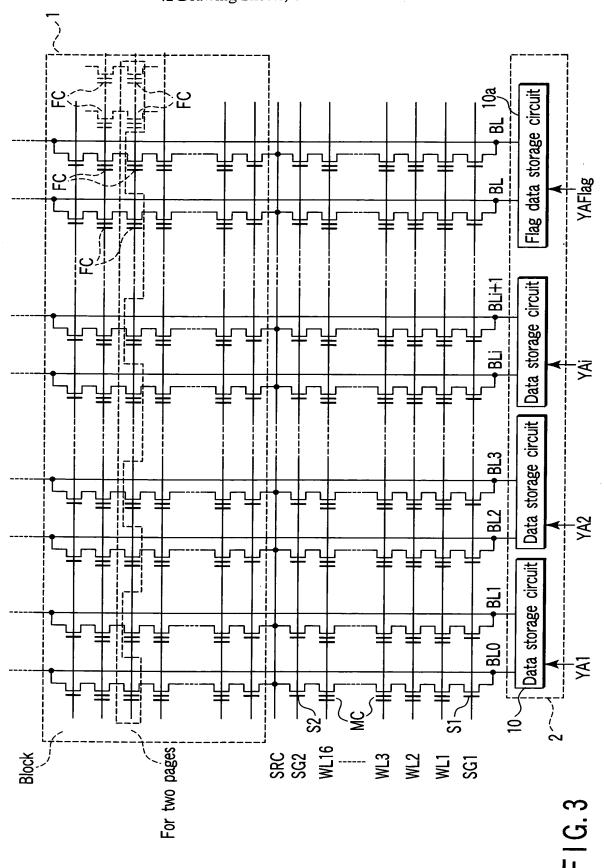
Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 2 of 42



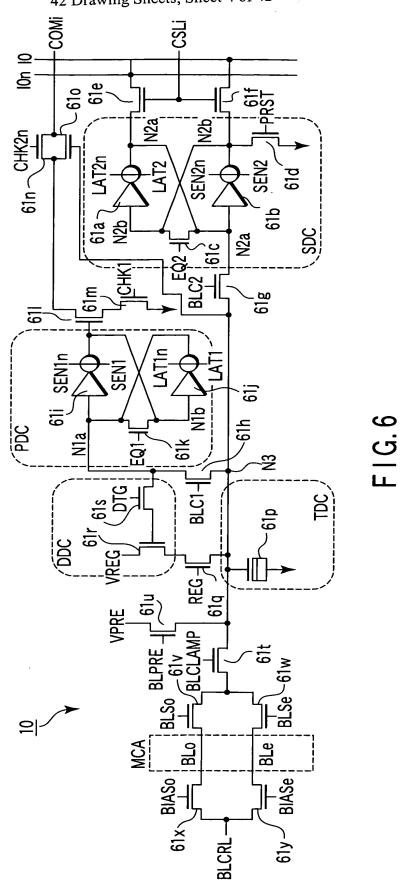




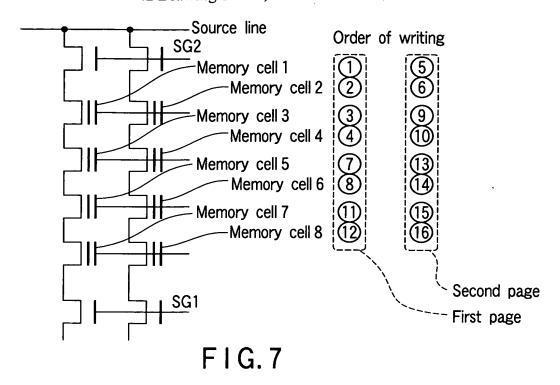
Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 3 of 42

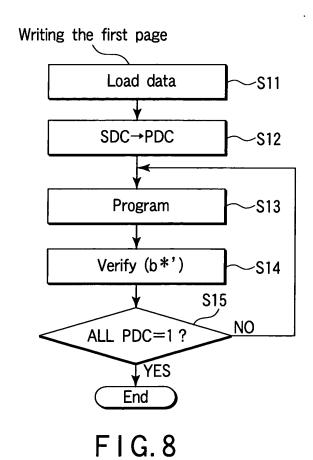


Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 4 of 42



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Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 6 of 42

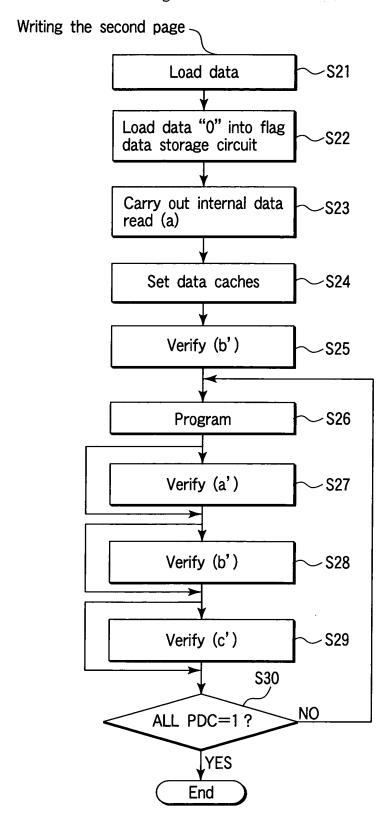


FIG. 9

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 7 of 42

Data in memory cell after writing 0 SDC

After data load and internal read

က

~

0

0

PDC

1 Data read by internal read	
0	
0	
PDC	
F I G. 10A	

Data to be written and read inputted from the outside world

After setting data caches	g data ca	ches			
	Data in	memory	Data in memory cell after writing	writing	
	0		2	က	
SDC	-	-	0	0	Used for charging in verifying memory cell data 1
DDC	0	1	-	0	Used for charging in verifying memory cell data 2
PDC	1	0	0	0	1 : Write unselected 0 : Write

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 8 of 42

After internal data read Copy data in SDC into PDC Copy data in TDC into SDC Copy data in PDC into TDC Copy data in PDC into DDC Copy data in TDC into PDC data in PDC into Data in memory cell after writing VREG=L, REG=H VREG=L, REG=H TDC=H See Do က က PDC က Data cache setting procedure က ~ SDC

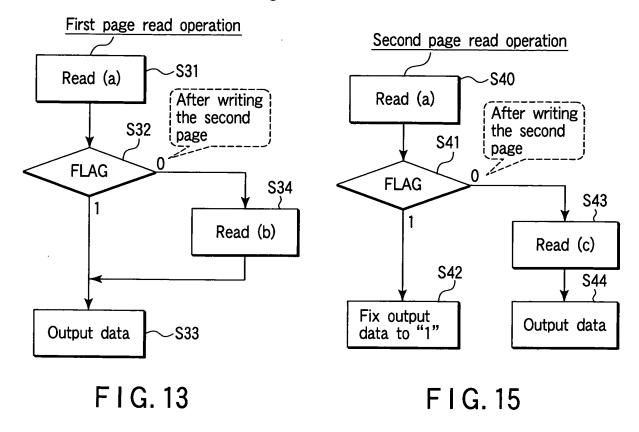
F1G 11

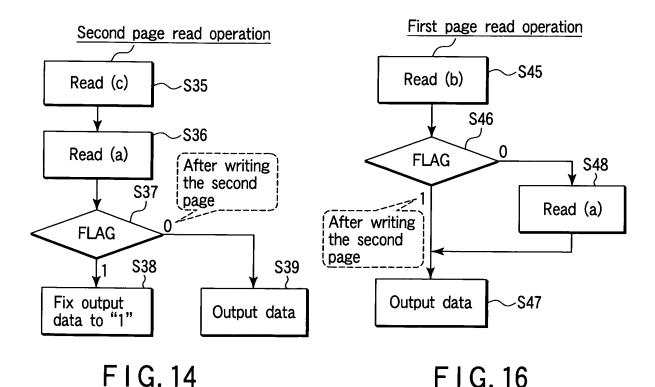
Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 9 of 42

	_							
TDC=H	VREG=L, REG=H	Copy data in PDC into DDC	Copy data in TDC into PDC	TDC=L	VREG=H, REG=H	Copy data in PDC into DDC	Copy data in TDC into PDC	•
	(0	0	0	0	(0	0	0	
1	1	1	-	0	0	0	0	ာ
1	1	-	-	0	0	0	0	TPC
	0)	0)	0	0				
0	0	0	(0	0	0	0	(0	
0	0	0	1	-	[-]	-	0	PDC
0	0	0	l	-	1	ı	0	П
_/	(1	1	0)	0	0)	0		:
	-	(0	0	0	0	(0)	0	
0	0	0	0	0	0	1		DDC
0	0	0	0	0	0	1	-	10
	-		-		-	0)	0	
0	0	0	0	0	0	0	0	
0	0	0	0	0	0	0	0	SDC
-	-	-	-	-		-	-	S
-	-	-	-		-	-	-	

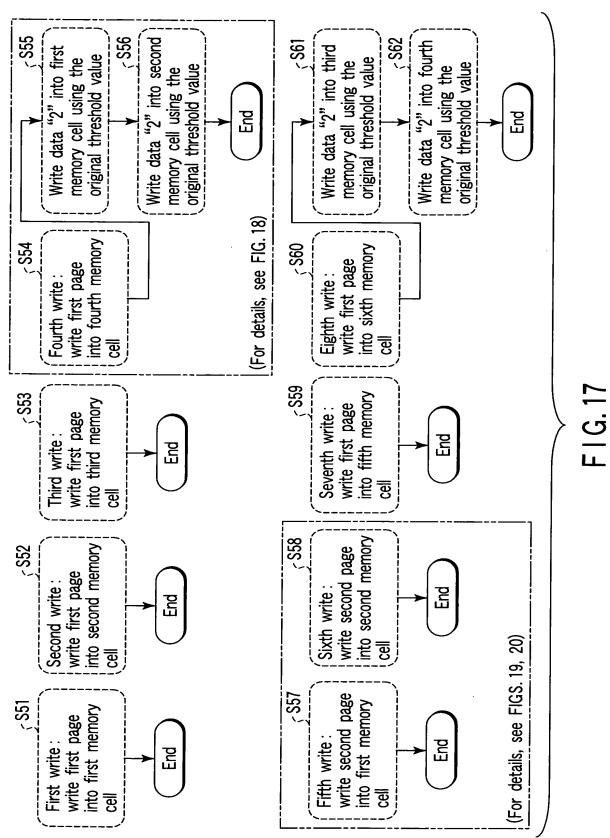
F1G. 12

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 10 of 42

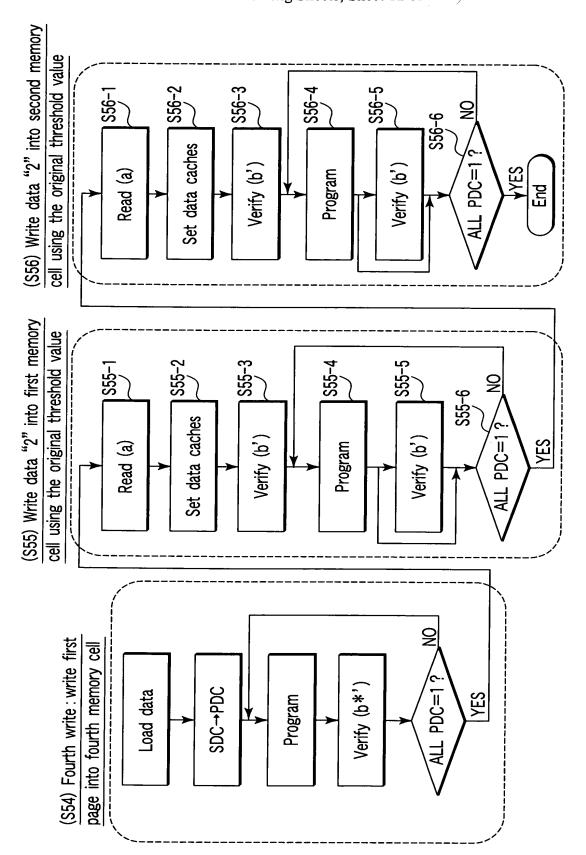




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F I G. 18

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 13 of 42

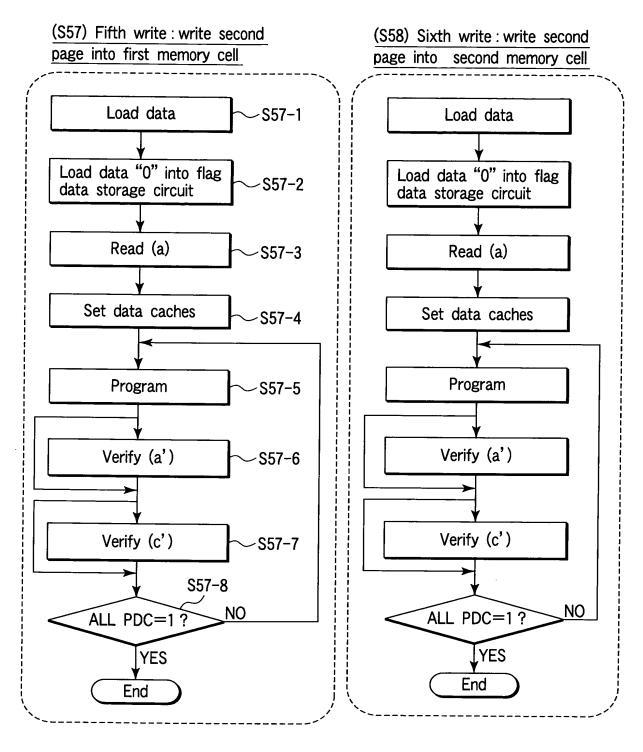


FIG. 19

FIG. 20

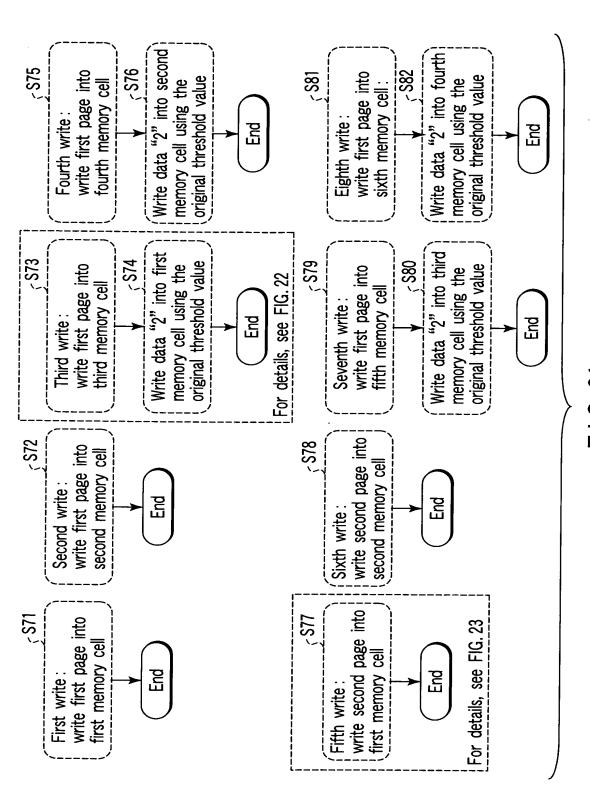


FIG. 21

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 15 of 42

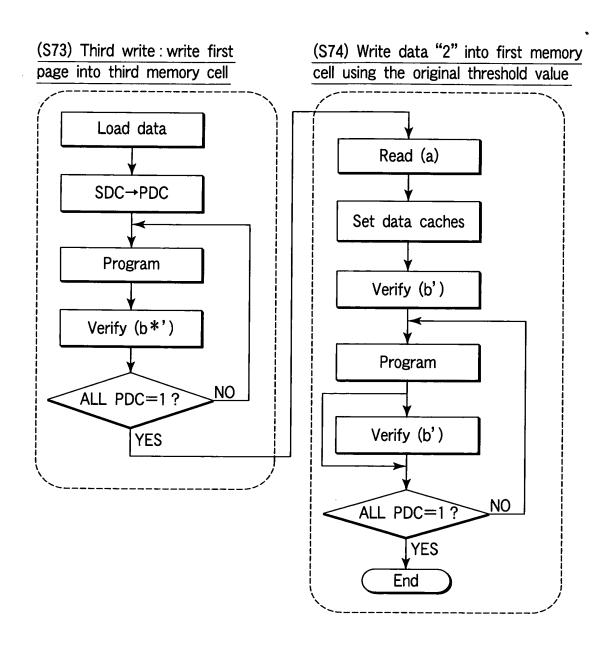
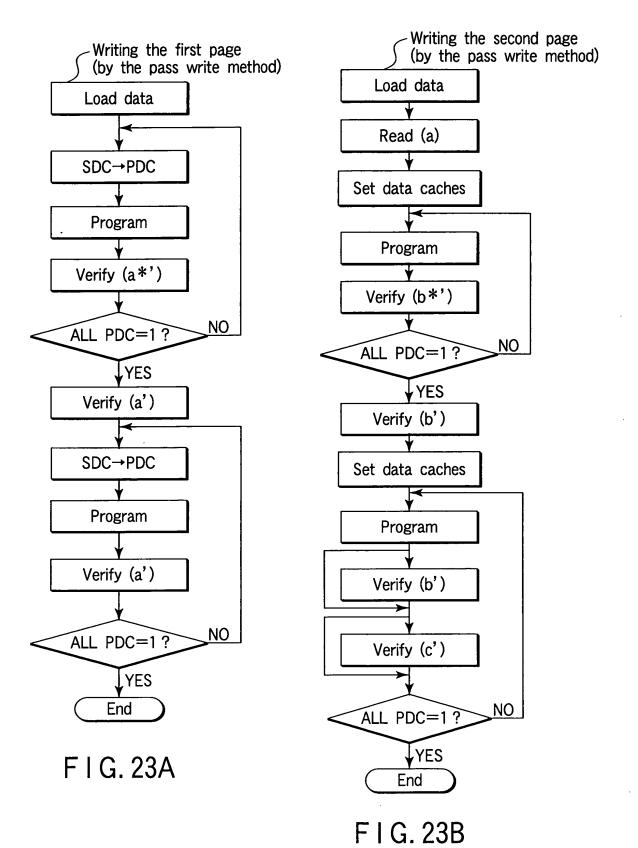


FIG. 22

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Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 17 of 42

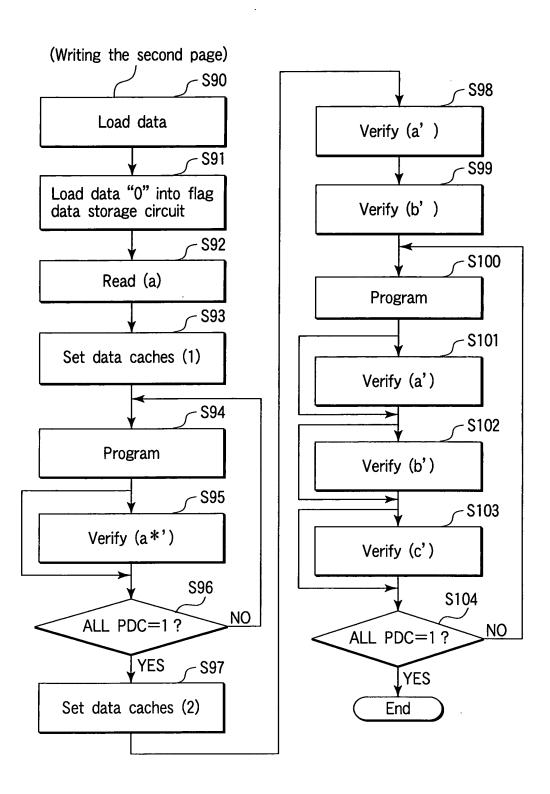


FIG. 24

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 18 of 42

Data cache setting 1

Data in memory cell after writing

0 1 2 3

SDC 1 0 0 1

F1G. 25

1: Write unselected 0: Write

0

0

DDC

0

PDC

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 19 of 42

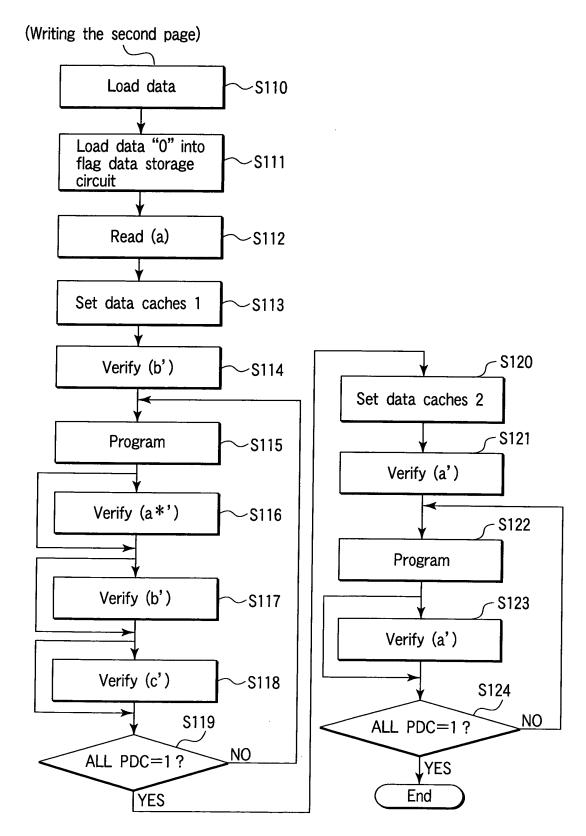


FIG. 26

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~

Used for charging in verifying memory cell data

0

1: Write unselected 0: Write

0

Used far charging in verifying memory cell data 1

0

in memory cell after writing 0 0 0 Data cache setting 1 Data 0 0 0 200 SDC

က

1: Write unselected 0: Write Data in memory cell after writing က 0 Data cache setting 2 0

Hogan & Hartson 81790.0303
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Semiconductor Memory Device...
EV 324 110 675 US
42 Drawing Sheets; Sheet 21 of 42

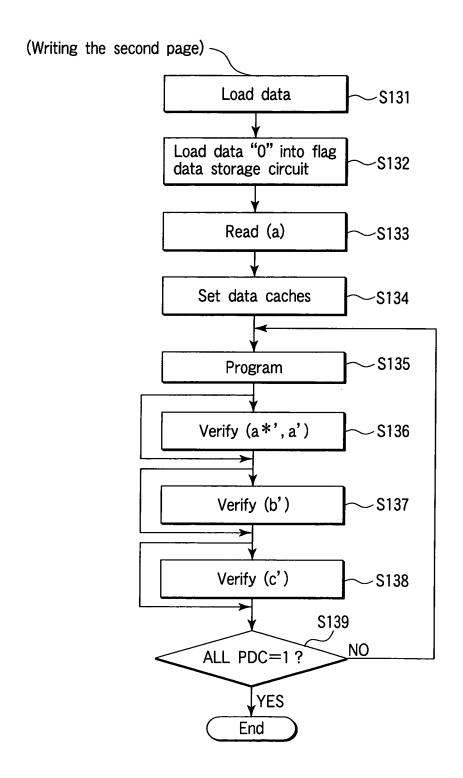


FIG. 28

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 22 of 42

After data load and internal read

	Data in	memory	memory cell after writing	writing.	
	0	-	2	3	
OOS	1	0	0	-	Data to be written and read inputted from the outside world
PDC	0	0	-	-	Data read by internal read

After data cache setting

FIG. 29A

	Data in	memory	memory cell after writing	writing	
	0	1	2	က	
SDC	0	l	-	0	0 Used for charging in verifying memory cell data 2
DDC	1	0		_	Used for precharging bit line in programming and for charging in verifying memory cell data 1
PDC	1	1/0	0	0	0 1:Write unselected 0:Write

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 23 of 42

	Precha	Precharge bit line on	ie on the k	the basis of the data in DDC	ie data in	DDC
		Data	Data in memory cell after writing	cell after	writing	
		0	-	2	3	
FIG. 30A	Bit line	ρρΛ	F (Vss)	Vdd	Ndd	
	With BI	With BLC1 = Volamp,		connect PDC to bit line	o bit line	
		Data i	Data in memory cell after writing	cell after	writing	
		0	-	2	က	
F1G.30B	Bit line	Ndd	0/Inter- mediate	0	0	
	During	program	recovery, t	ransfer da	ta in PDC	During program recovery, transfer data in PDC to DCC, invent data in DDC, and transfer the inverted data to PDC
		Data i	Data in memory cell after writing	cell after	writing	
		0	_	2	က	
	SDC	0	_	-	0	Used for charging in verifying memory cell data 2
	DDC	-	1/0	0	0	1 : Write unselected 0 : Write
F1G 30C	PDC	0	-	0	0	Used for precharging bit line in programming and for charging in verifying memory cell data 1
5.5						

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Verify (a)
Charge bit line on the basis of data in PDC
Discharge bit line at a potential of WL = a*
Invert data in PDC while discharging bit line

	Data in	memory	in memory cell after writing	writing .	
	0		2	က	
SDC	0	1	_	0	Used for charging in verifying memory cell data 2
DDC	-	0/1	0	0	1 : Write unselected 0 : Write
PDC	_	0	-	-	Used far precharging bit line in programming and for charging in verifying memory cell data 1

Load the potential of bit line into TDC With VREG = H and REG = H, make TDC 1 when dynamic data is 1 Transfer data in PDC ta DDC and data in TDC to PDC

F1G. 31A

	Data in	memory	memory cell after writing	writing	
	0	-	2	က	
SDC	0	1	1	0	Used far charging in verifying memory cell data 2
DDC	-	0	0	_	User for precharging bit line in programming and for chagrining in verifying memory cell data 1
PDC	-	0/1	-	-	1 : Write unselected 0 : Write

F1G.31B

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets: Sheet 25 of 42

With WL = a', discharge bit line With VREG = H and REG = H, set 1 in TDC when dynamic data is 1 Transfer data in PDC to DDC Transfer data in TDC to PDC Transfer data in TDC to PDC

		Used for charging in verifying memory cell data 2	1: Write unselected 0: Write	Used for precharging bit line in programming and for charging in	verifying memory cell data 1
memory cell after writing	3	0	0	-	
cell afte	2	-	0	_	
memory		_	0/1	0	
Data in	0	0	_	_	
		SDC	DDC	PDC	-

Transfer data in DDC to PDC Then, transfer data in PDC to DDC

FIG. 32A

		Used for charging in verifying memory cell data 2	Used for precharging bit line in programming and for charging in verifying memory cell data 1	1 : Write unselected 0 : Write
writing	က	0	-	0
emory cell after writing	2	-	-	0
memory	1	-	0	0/1
Data in me	0	0	-	-
		SDC	DDC	PDC

FIG. 32B

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With memory cell data 1, all of the writing with verify (a*) is completed (the writing with verify (a') might nat be completed)

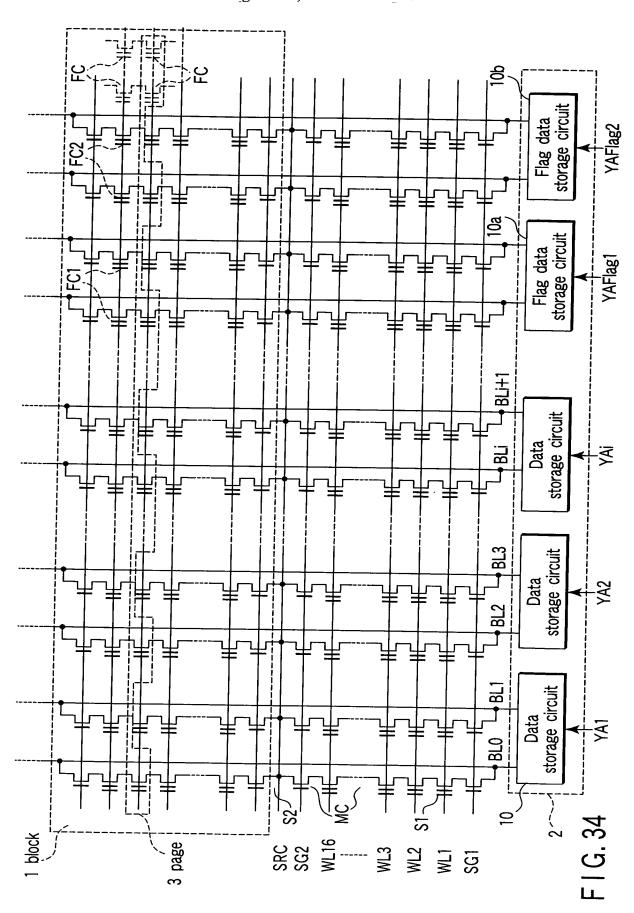
	Data in me	memory	mory cell after writing	writing	
	0		2	က	
SDC	0	-	-	0	Used far charging in verifying memory cell data 2
DDC	•	0	-	-	Used for precharging bit line in programming and for charging in verifying memory cell data 1
PDC	1	_	0	0	1 : Write unselected 0 : Write

With memory cell data 1, all of the writing with verify (a') is completed (the writing with verify (a') might not be completed)

	Data in men		nory cell after writing	writing	
	0	-	2	က	
SDC	0	-	-	0	Used for charging in verifying memory cell data 2
DDC			-	_	Used for precharging bit line in programming and for charging in verifying memory cell data 1
PDC	-	-	0	0	1 : Write unselected 0 : Write

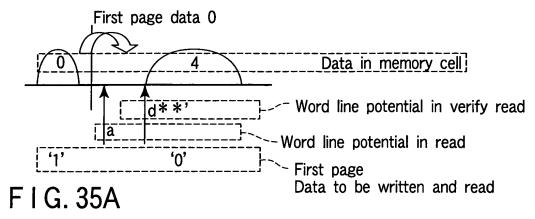
I G. 33B

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Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 28 of 42

(After writing first page and before writing second page)

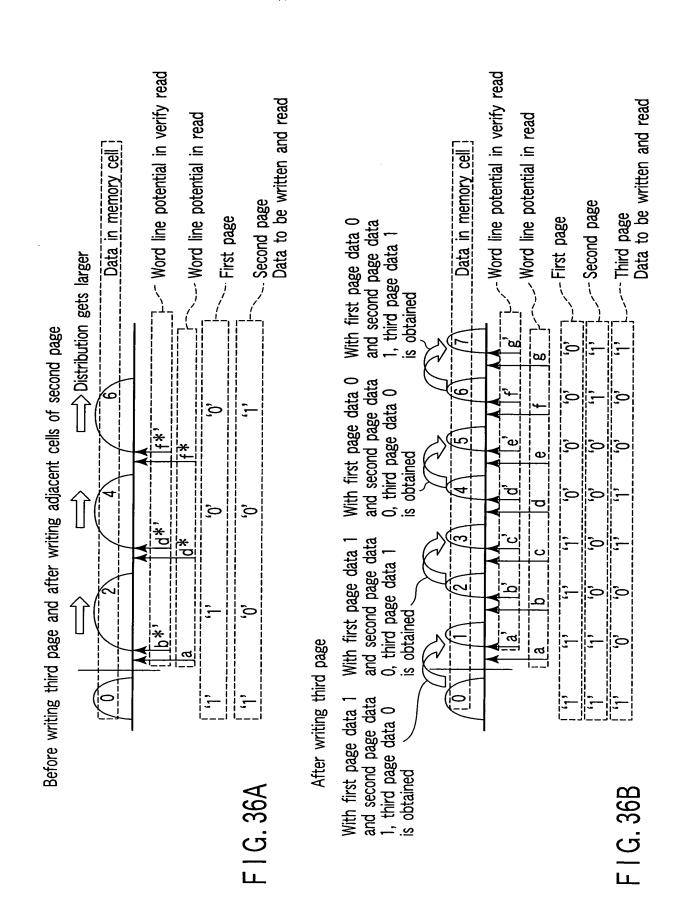


After writing first page, before writing second page, and after writing adjacent cells of first page Distribution gets larger Data in memory cell; d**; Word line potential in verify read Word line potential in read '0' First page Data to be written and read F I G. 35B After writing second page, before writing third page, and after writing adjacent cells of second page With first page data 1, With first page data 0, second page data 0 is second page data 1 is obtained obtained 6 Data in memory cell; Word line potential d*' in verify read Word line potential **'**0' **'**0' in read First page **'0' '0'** Second page Data to be

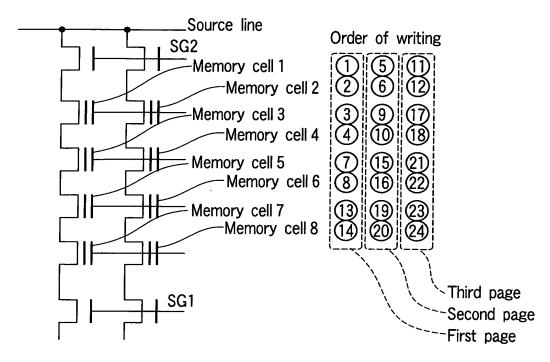
written and read

FIG. 35C

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F I G. 37A

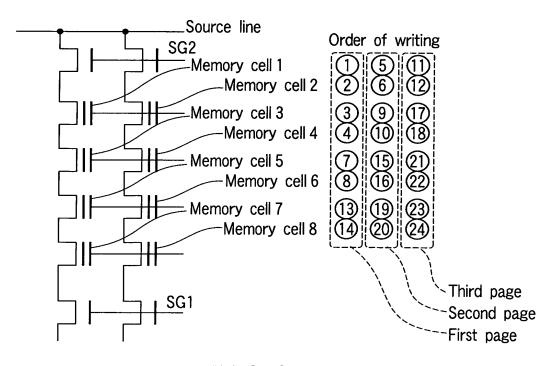
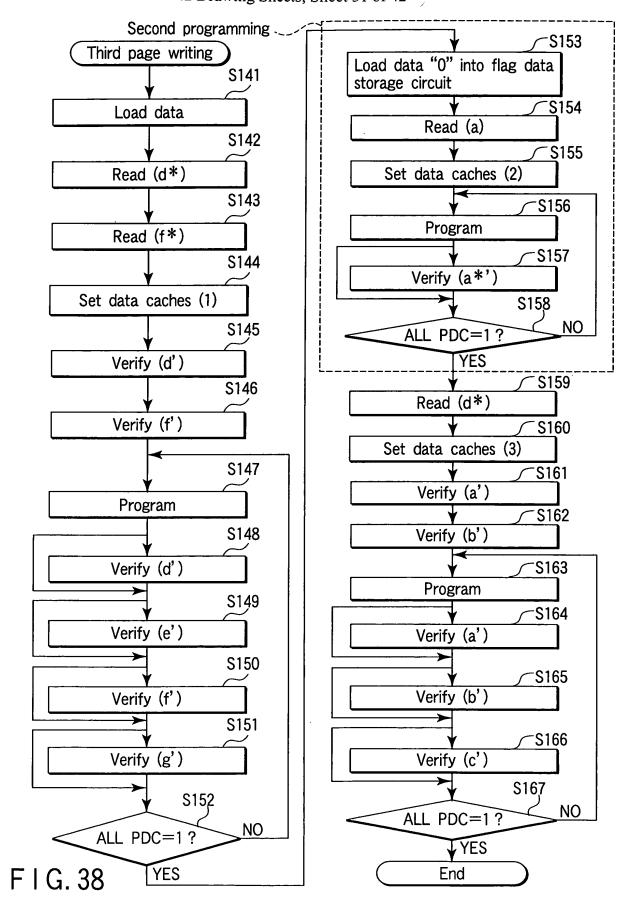


FIG. 37B

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Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 32 of 42

After third page data load internal read 1

		1 0 0 1 Data to be written and read inputted from the outside world	0 0 0 1 1 Data to be read by internal read	1 Data to be read by internal read
B	7	-	-	-
writin	9	0	-	-
memory cell after writing	2 3 4 5 6 7	0	0	0 0 1 1
cell	4	-	0	-
mory	3	-	0	0
n me	2	0	0	0
Data in	-	0	0	0
<u>ப</u>	0	-	0	0
		SDC	DDC	PDC

After third page data cache setting 1

		Data in		mory	memory cell after writing	after	writin	0.0	
	0	-	2	က	3 4 5 6 7	5	9	7	
SDC	-	-	-	-	_	-	0	0	1 1 0 0 Used far charging in verifying memory cell data items 5, 4
ODC	0	-	-	0	0	-	-	0	0 0 1 1 0 Used for charging in verifying memory cell data 6 Forced to be at VSS in verifying memory cell data 4
PDC	-		-	_	0	0	0	0	1 0 0 0 1: Write unselected 0: Write

IG. 39B

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 33 of 42

After third page data cache setting 2

				1 : Write unselected 0 : Write
D0	7	0	0	1
memory cell after writing	မ	0	-	-
after	5	0 0 0	-	-
e lleo	4	0	0 0	
mory	2 3	0	0	-
n me	2	0	-	-
Data in	1	-	1	0
۵	0	-	0	-
		SDC	DDC	PDC

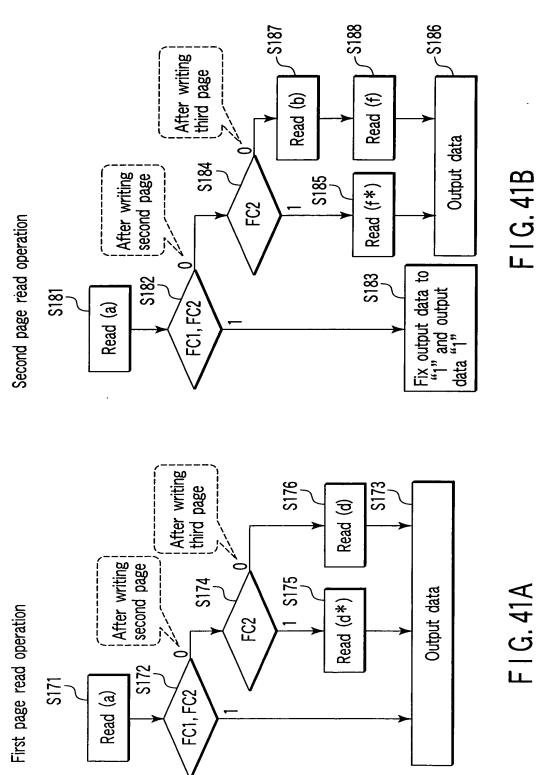
After third page data cache setting 3

F I G. 40A

		Data in	n mei	memory cell after writing	cell	ıfter	writin	Ø	
	0	-	2	2 3 4 5 6 7	4	5	9	7	
OOS	,	-	0	0	0	0	0	0	0 0 0 0 Used for charging in verifying memory cell data 1
oda	0	_	-	0	0	-	-	0	1 0 0 1 1 0 Used for charging in verifying memory cell data 2
PDC	-	0	0	0 0 1 1 1	1	-	-	1	1 : Write unselected 0 : Write

1 G. 40B

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Third page read operation

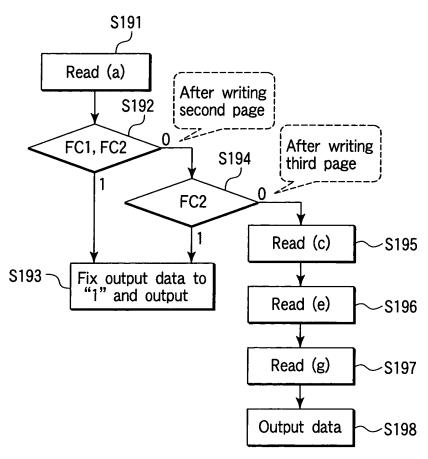


FIG. 42

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After data load and internal read

	Data in	_	nemory cell after writing	writing	
	0		2	လ	
SDC	1	0	0	-	Data to be written and read inputted from the outside world
PDC	0	0	1	•	Data read by internal read

F I G. 43A

After setting data caches

	Data in	<u>-</u>	nemory cell after writing	writing	
	0		2	3	
SDC		1	0	0	Used for charging in verifying memory cell data 1
DDC	0	0	L	0	Used for charging in verifying memory cell data 2
PDC	-	0	0	0	1 : Write unselected, 0 : Write

FIG. 43B

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 37 of 42

Verify (a*')
Charge bit line on the basis of data in SDC
Discharge bit line at a potential of WL=a*'

	Data in	Data in memory cell after writing	cell after	writing	
	0		2	က	
SDC	-	1	0	0	Used for charging in verifying memory cell data 1
DDC	0	0	-	0	Used for charging in verifying memory cell data 2
PDC	1	0	0	0	1 : Write unselected, 0 : Write

F I G. 44A

Set Vdd in TDC and transfer the potential of bit line to TDC when BLCLAMP is H With VREG=H, REG=H, make TDC 1 when dynamic data is 1 Transfer data in PDC to DDC and data in TDC to DDC

	Data ir	Data in memory cell after writing	cell after	writing	
	0	-	2	က	
SDC	-	-	0	0	0 Used for charging in verifying memory cell data 1
DDC		0	0	0	0 1: Write unselected, 0: Write
PDC	0	0/1	•	0	Used for charging in verifying memory cell data 2 When threshold voltage in memory cell into which data 1 is written exceeds a*' → 1

F I G. 44B

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 38 of 42

Discharge bit line at a potential of WL=a' Set Vdd in TDC and transfer the potential of bit line to TDC when BLCLAMP is H With VREG=H, REG=H, make TDC 1 when dynamic data is 1 Transfer data in PDC to DDC and data in TDC to DDC

	Dz	Data in memory cell after writing	mory cell	after writi	ng	
	0	1pass	1pass 1fail	2	က	
SDC	-	-	-	0	0	0 0 Used for charging in verifying memory cell data 1
DDC	0	_	0/1		0	Used for charging in verifying memory cell data 2 When threshold voltage in memory cell into which data 1 is written exceeds $a^* \rightarrow 1$
PDC	1	1	0	0	0	0 1 : Write unselected, 0 : Write

F1G. 45A

Hogan & Hartson 81790.0303 Noboru SHIBATA et al. Semiconductor Memory Device... EV 324 110 675 US 42 Drawing Sheets; Sheet 39 of 42

Charge bit line on the basis of data in DDC Discharge bit line at a potential of WL=b' Transfer data in DDC to TDC, PDC to DDC and TDC to PDC during the discharge Set Vdd in TDC and transfer the potential of bit line to TDC when BLCLAMP is H Transfer data in PDC to DDC and data in TDC to DDC

F I G. 45B

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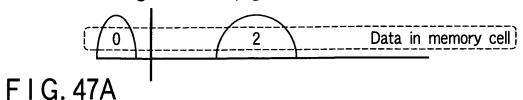
Transfer data in DDC to TDC, PDC to DDC and TDC to PDC during the discharge Set Vdd in TDC and transfer the potential of bit line to TDC when BLCLAMP is H With VREG=H, REG=H, make TDC 1 when dynamic data is 1 Charge bit line Discharge bit line at a potential of WL=c'

	Da	ita in mer	Data in memory cell after writing	after writi	Bu	
	0		1 2 3fail 3pass	3fail	3pass	
SDC	1		0	0	0	0 Used for charging in verifying memory cell data 1
DDC	0	0/1	-	0	0	Used for charging in verifying memory cell data 2 When threshold voltage in memory cell into which data 1 is written exceeds $a^* \rightarrow 1$
PDC	-	0	0	0	-	1 : Write unselected, 0 : Write

F1G 46

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Before writing the second page



After writing the second page

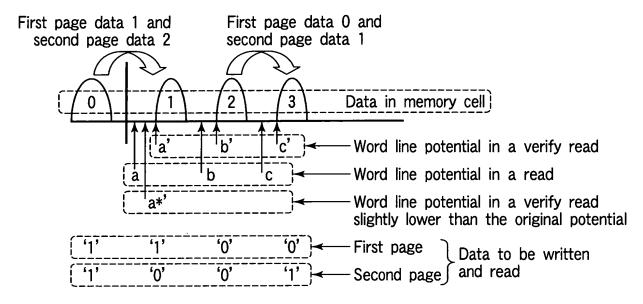
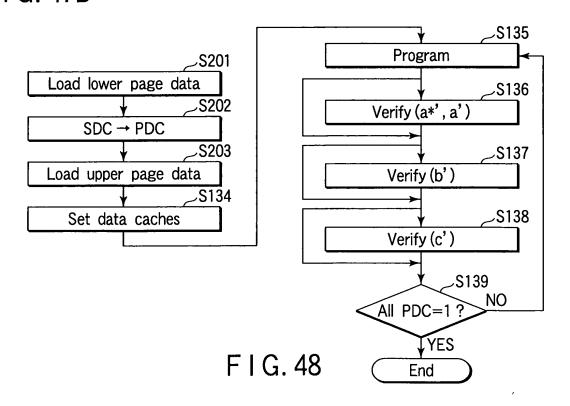


FIG. 47B



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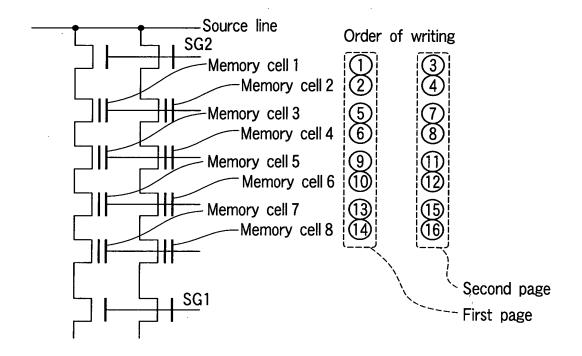


FIG. 49